Serial No.: 10/616,155 Group Art Unit: 2811

Amendments to the Abstract:

Please replace the Abstract with the following rewritten Abstract:

--The present invention disclosure relates to a method for fabricating an image sensor capable of improving [[a]] dark current characteristics. The method includes: the steps of: forming sequentially a pad oxide layer and a pad nitride layer on a substrate and selectively removing a portion of the pad oxide layer and a first portion of the pad nitride layer to expose a surface of the substrate [[in]] on which a field insulation layer will be formed; forming the field insulation layer a first ion-implantation region by performing a first channel stop ionimplantation process [[to]] on the exposed surface of the substrate with use of using the remaining pad nitride layer that exists after removal of the first portion of the pad nitride layer as a first mask; performing a thermal oxidation process to form the field insulation layer on the exposed surface of the substrate; removing a partial second portion of the pad nitride layer so that [[one]] a side of the remaining pad nitride layer that exists after removal of the second portion of the pad nitride layer is spaced out with a predetermined distance from an edge of the field insulation layer; apart from an edge of the field insulation layer by a distance; and forming a second ion-implantation region by performing an additional a second ion-implantation process onto on the exposed substrate surface and the field insulation layer [[by]] using the remaining pad nitride layer that exists after removal of the second portion of the pad nitride layer as a second mask .--